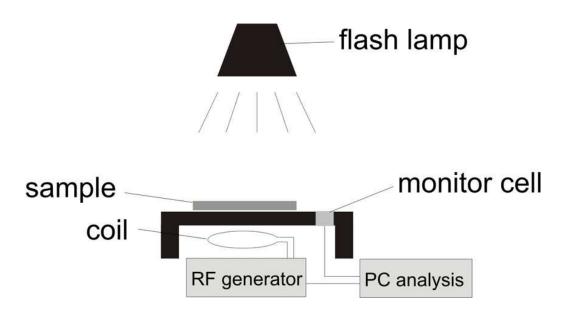
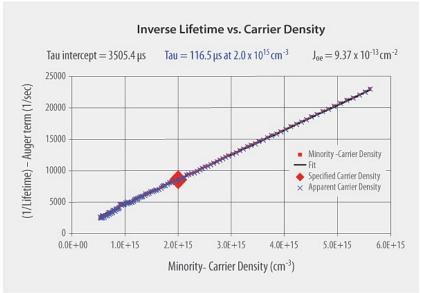


## <u>Sinton Carrier Lifetime Tester – WCT 120</u>

- Measure Lifetime of electron,
  Resistivity, Saturation Current Density,
  Trap Density, Implied V<sub>oc</sub> at 1-sun
- Test lifetimes Range : 100 ns to greater than 10 ms.
- Wafer thickness range: 10–2000 µm
- Calibrated injection range: 10<sup>13</sup>–10<sup>16</sup> cm<sup>-3</sup>







## Nanofabrication CORE Facility